

FAST - (10599830.wsp.1)

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L4: (29) 3 and test adj structure

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L6: (286) 2 and test adj structure

L7: (4849) 324/158.1.ccls.

L8: (130) 2 and 7

L9: (12) 8 and test adj structure

L10: (8982) 324/765,763,158.1,719.ccls.

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	U	1	Document ID	Issue Dat	Pages	Title	Current OR	Current XR	Retrieval	Inventor	S	C	P	2	3	5
1			US 6788074	20040907	14	System and method for using a capacitance mea	324/663	324/765;		Sarma; Robin C. et al.						
2			FR 2780162	19991224	14	Test structure for measurement of multilav		438/17;		FROMENT, B						
3			EP 1116957	20010718	6	Circuit for measuring capacitances of structu				LINDOLF, J et al.						
4			US 6366098	20020402	14	Test structure, integrated circuit, and	324/678	324/158.1;		Froment; Benoit						
5			US 6404222	20020611	11	Chip capacitance measurement circuit	324/765	324/537;		Fan; Chen-Teng et al.						
6			US 6501283	20021231	6	Circuit configuration for measuring the capac	324/679	324/519;		Lindolf; Jurgen et al.						
7			US 6700399	20040302	11	High density parasitic measurement structure	324/765	324/761;		Savithri; Nagaraj						
8			US 5999010	19991207	6	Method of measuring interconnect coupling c	324/765	438/18		Narasimh						
			A					324/658		Arora; Narain D. et al.						

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